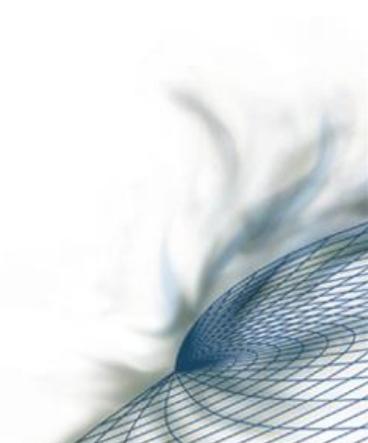


Nondestructive Evaluation of Cold Spray Repairs

Zach Thomas, Stuart Chaplan, Vladimir Zilberstein, Neil Goldfine

JENTEK Sensors, Inc., 110-1 Clematis Avenue, Waltham, MA 02453-7013
www.jenteksensors.com • Phone: 781-642-9666 • Email: jentek@jenteksensors.com

JENTEK issued and exclusively licensed patents include U.S. Patent #s 8,222,897, 8,050,883, 7,994,781, 7,876,094, 7,812,601, 7,696,748, 7,589,526, 7,533,575, 7,528,598, 7,526,964, 7,518,360, 7,467,057, 7,451,657, 7,451,639, 7,411,390, 7,385,392, 7,348,771, 7,289,913, 7,280,940, 7,230,421, 7,188,532, 7,183,764, 7,161,351, 7,161,350, 7,106,055, 7,095,224, 7,049,811, 6,995,557, 6,992,482, 6,952,095, 6,798,198, 6,784,662, 6,781,387, 6,727,691, 6,657,429, 6,486,673, 6,433,542, 6,420,867, 6,380,747, 6,377,039, 6,351,120, 6,198,279, 6,188,218, 6,144,206, 5,966,011, 5,793,206, 5,629,621, 5,990,677 and RE39,206 (other US/foreign patents issued and pending).



Outline

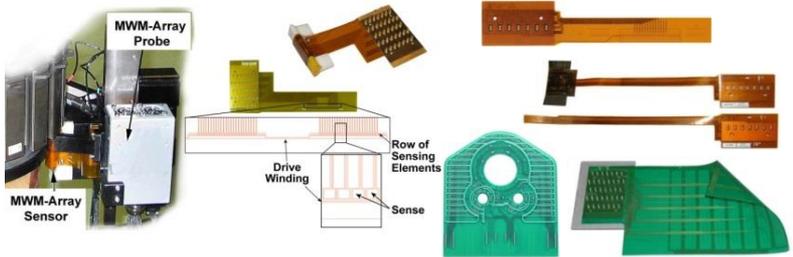
- Technology Overview
- Success Story Examples
- Coating Thickness Measurement
- Disbond Detection and Imaging
- Cold Spray Coating Thickness and Quality
- Proposed Future Work



Core JENTEK Technologies

MWM®-Arrays

- Patented scanning and embeddable Eddy Current Sensor product
- Two decade lead** over all technology in the market
Solving problems that have been unsolved for decades
Strong IP position

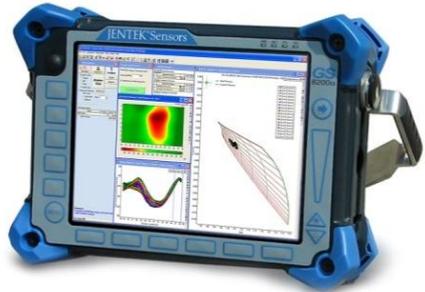


GridStation® Systems

- Portable and Hand-Held versions



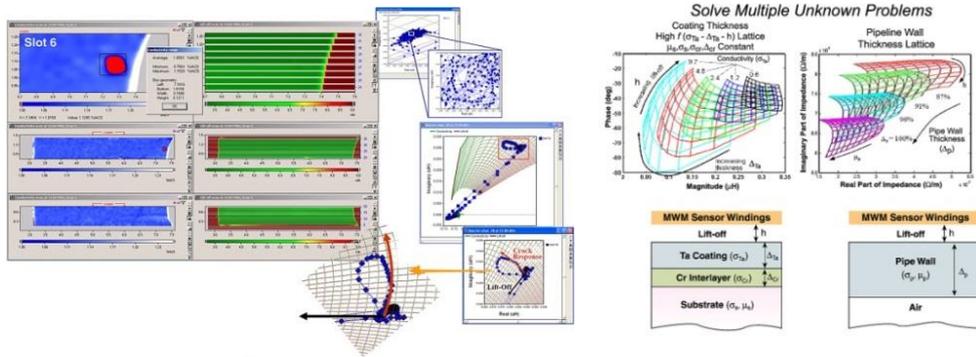
**Delivered
GS-D8000β**



**Next Generation
GS-8200α**

GridStation® Software using Hyperlattices™

- Performs multivariate inverse methods – i.e. fast, autonomous data analysis for decision support in NDT, CBM and SHM

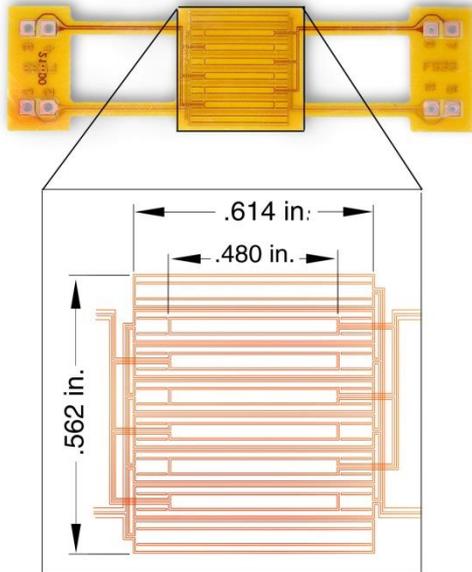


Fuzzy-Hyperlattices

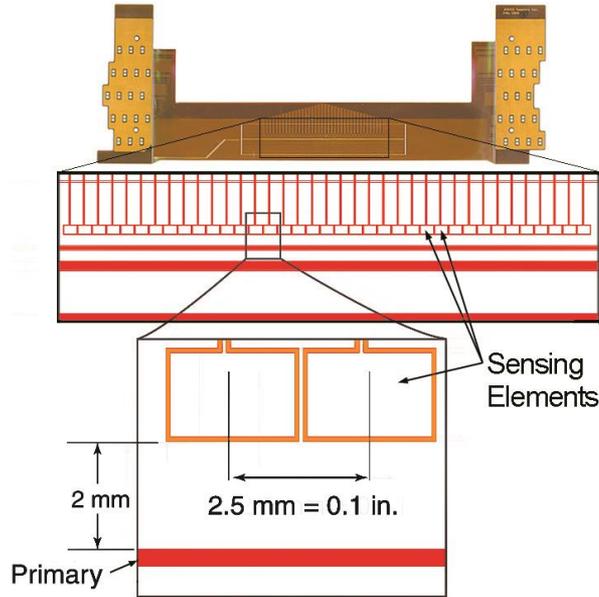
- Remaining Useful Life Prediction (RUL) and rapid uncertainty estimation

MWM® & MWM-Array Eddy Current Sensors

Single-channel
MWM sensor FS33



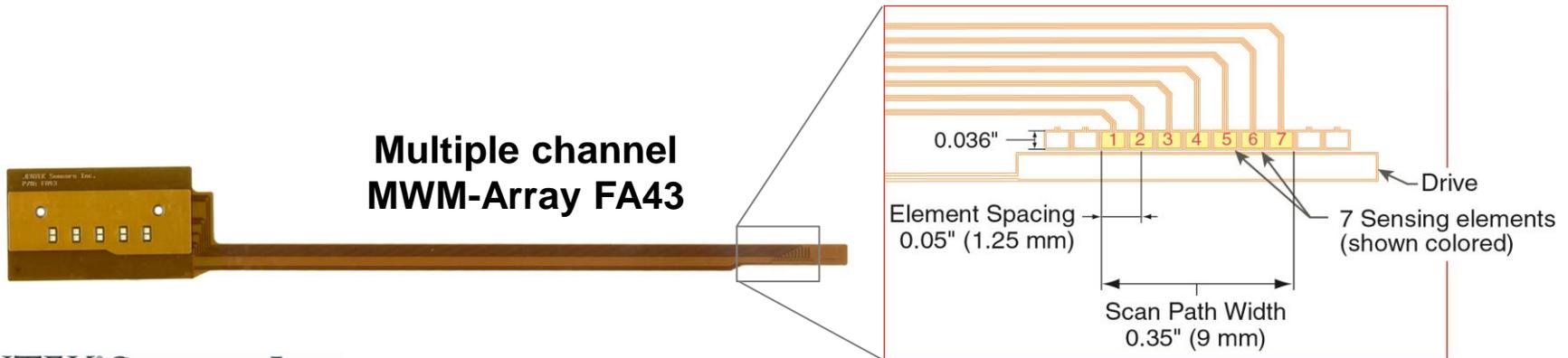
Multiple channel
MWM-Array sensor FA24



Paradigm Shift

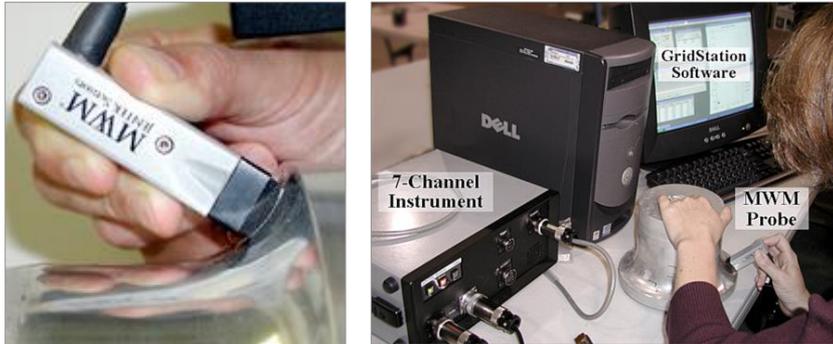
*Design Sensors
with rapid and
accurate
modeling as the
primary focus*

Multiple channel
MWM-Array FA43



Example JENTEK MWM & MWM-Array Success Stories

Air Force/Navy Propeller Cold Work

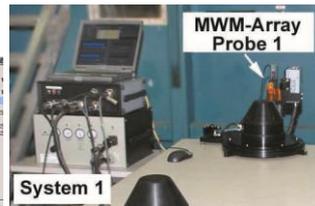
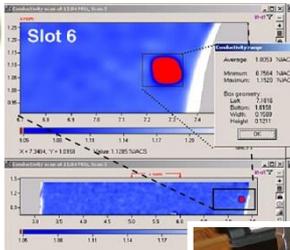
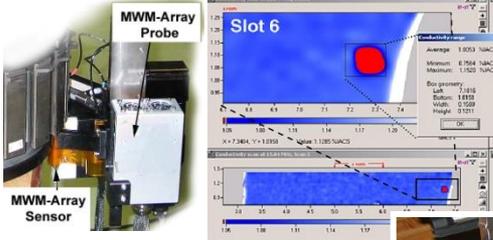


NASA Space Shuttle Leading Edge

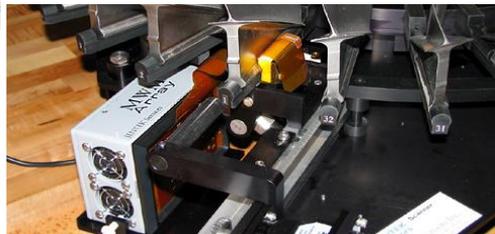


Navy Disk Slot Inspection & Blade Dovetail Inspection

Disk Slot Inspection



Blade Dovetail Inspection



Engine Component Inspection

Rolls-Royce AE SERIES PROPULSION SYSTEM Service Bulletin Index. LIST OF AE 3007A SERIES SERVICE BULLETINS.

SB No.	Rev No.	Title	Compliance Category	Date	Models Affected	Module or ATA Locator
AE 3007A-F2-386		See AE 3007A-A-F2-386				
AE 3007A-F2-388	1	Engine - 6th thru 13th Stage Compressor Wheel Krity Edge Seals - Jantek Eddy Current Inspection	8	09-May-11	7A, 7A1-1, 7A1-2, 7A1, 7A1E, 7A1P, 7A2, 7A2	72-37-00

MWM-Array FA43 Sensor

“Technical aspects of the method are FAA approved.”

Coating Thickness Measurements



Designation: E 2338 – 06

Standard Practice for Characterization of Coatings Using Conformable Eddy-Current Sensors without Coating Reference Standards¹

This standard is issued under the fixed designation E 2338; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This practice covers the use of conformable eddy-current sensors for nondestructive characterization of coatings without standardization on coated reference parts. It includes the following: (1) thickness measurement of a conductive coating on a conductive substrate, (2) detection and characterization of local regions of increased porosity of a conductive coating, and (3) measurement of thickness for nonconductive coatings on a conductive substrate or on a conductive coating. This practice includes only nonmagnetic coatings on either magnetic ($\mu \neq \mu_0$) or nonmagnetic ($\mu = \mu_0$) substrates. This practice can also be used to measure the effective thickness of a process-affected zone (for example, shot peened layer for aluminum alloys, alpha case for titanium alloys). For specific types of coated parts, the user may need a more specific procedure tailored to a specific application.

1.2 Specific uses of conventional eddy-current sensors are covered by Practice D 7091 and the following test methods issued by ASTM: Test Methods B 244, E 376, E 1004, and G 12.

D 7091 Practice for Nondestructive Measurement of Dry Film Thickness of Nonmagnetic Coatings Applied to Ferrous Metals and Nonmagnetic, Nonconductive Coatings Applied to Non-Ferrous Metals

E 376 Practice for Measuring Coating Thickness by Magnetic-Field or Eddy-Current (Electromagnetic) Examination Methods

E 543 Specification for Agencies Performing Nondestructive Testing

E 1004 Practice for Determining Electrical Conductivity Using the Electromagnetic (Eddy-Current) Method

E 1316 Terminology for Nondestructive Examinations

G 12 Test Method for Nondestructive Measurement of Film Thickness of Pipeline Coatings on Steel

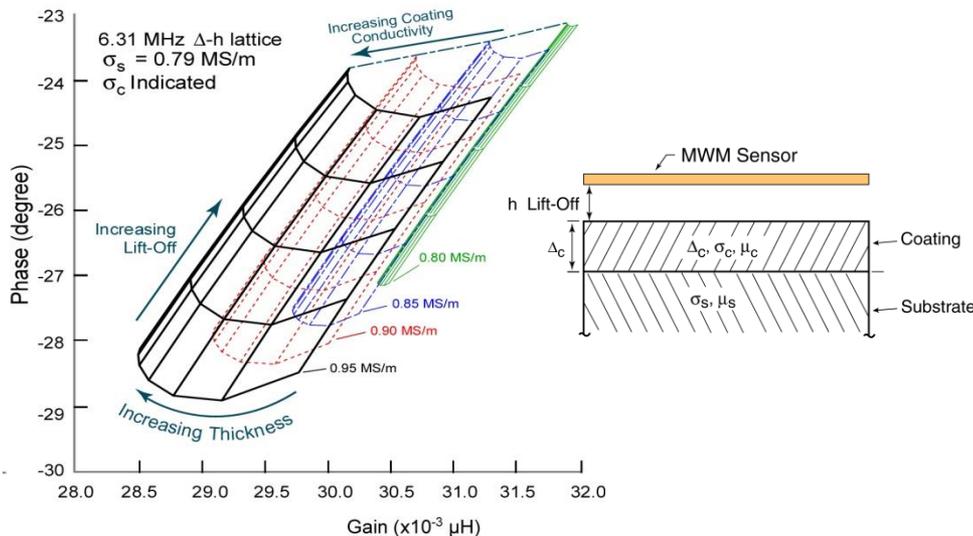
2.2 ASNT Documents:²

SNT-TC-1A Recommended Practice for Personnel Qualification and Certification in Nondestructive Testing

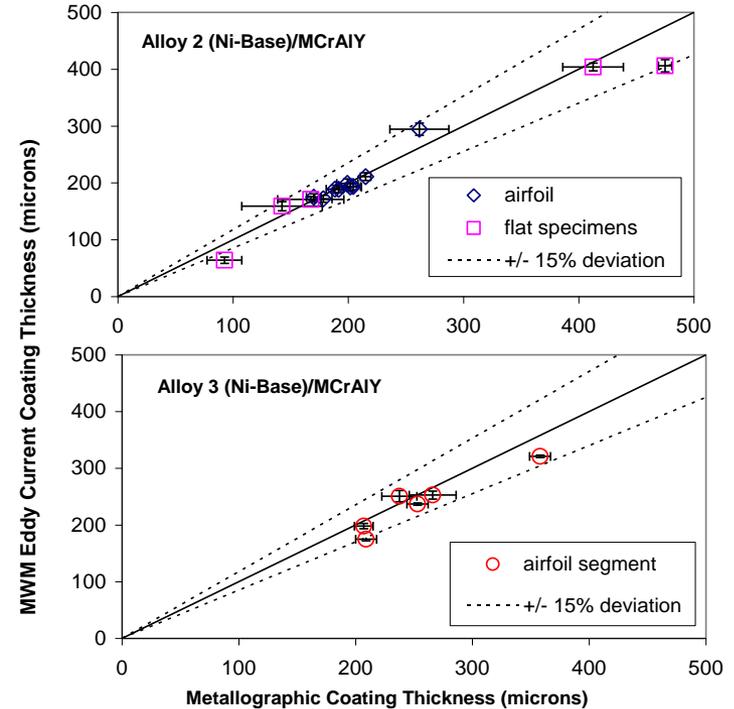
ANSI/ASNT-CP-189 Standard for Qualification and Certification of NDT Personnel

2.3 AIA Standard:

JENTEK Grid Lattice Four-Unknown Coating Problem Example



Comparison of MWM with Metallographic MCrAlY Coating Thickness Measurements



Independent Evaluation by Siemens

Published, proceedings of ASME/IGTI Turbo Conference, June 2003, Atlanta, GA

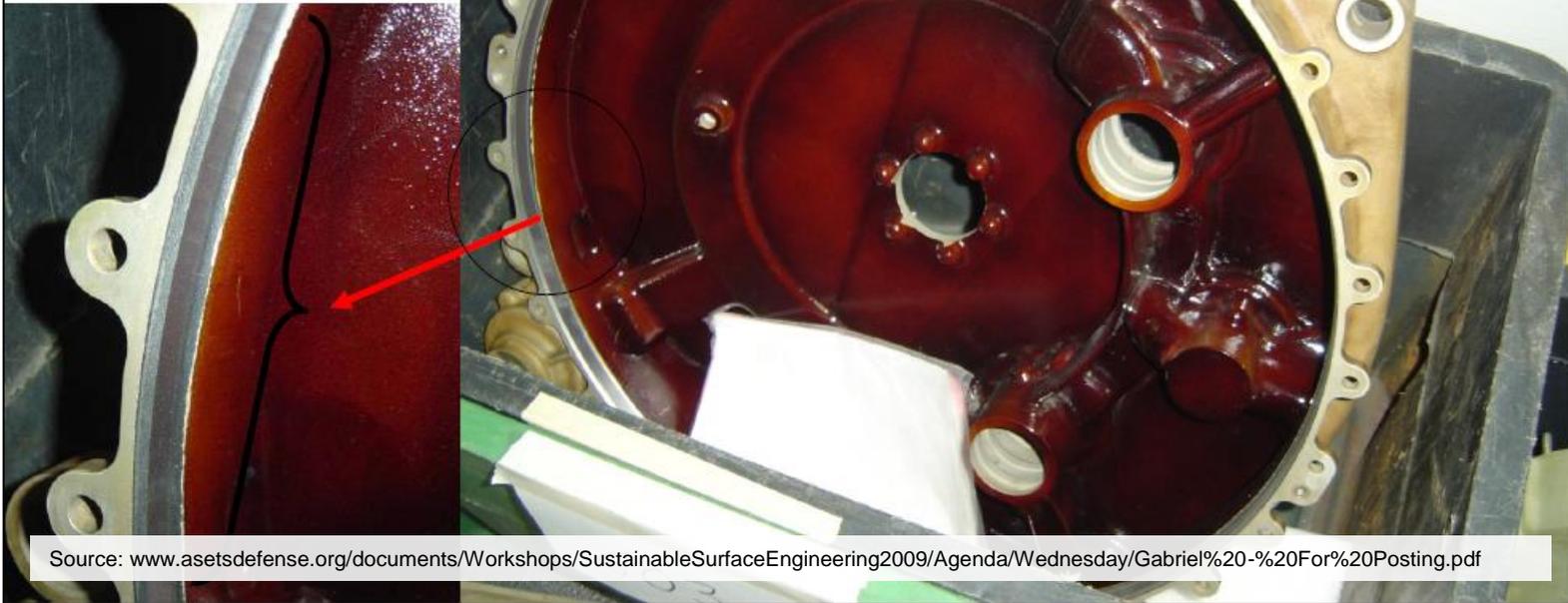
H-60 Sump Repair Sites



UH-60 Sump Assembly Main Module -Main Gearbox Repair



*Repair Site:
Rubber O-ring insert*



Source: www.asetdefense.org/documents/Workshops/SustainableSurfaceEngineering2009/Agenda/Wednesday/Gabriel%20-%20For%20Posting.pdf

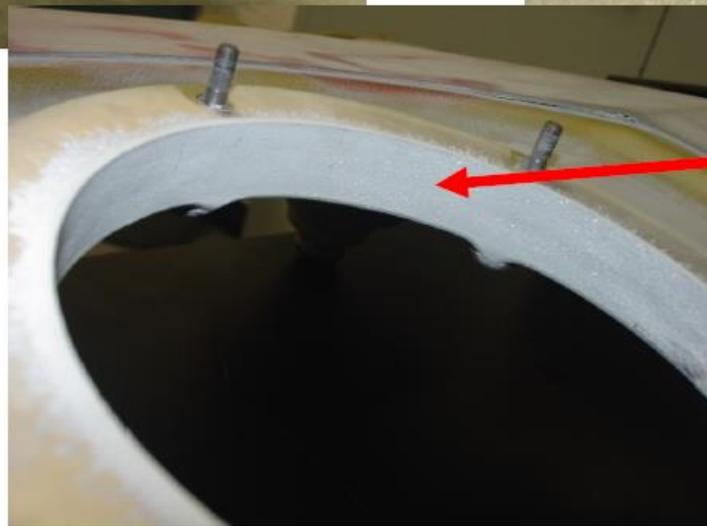
H-60 Sump Repair Sites



UH-60 Sump Assembly Main Module -Main Gearbox Repair



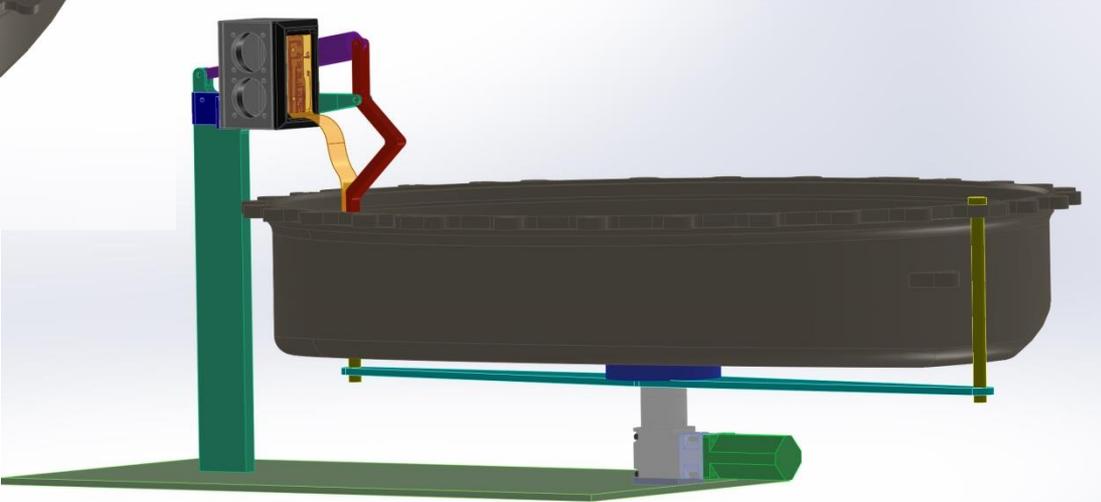
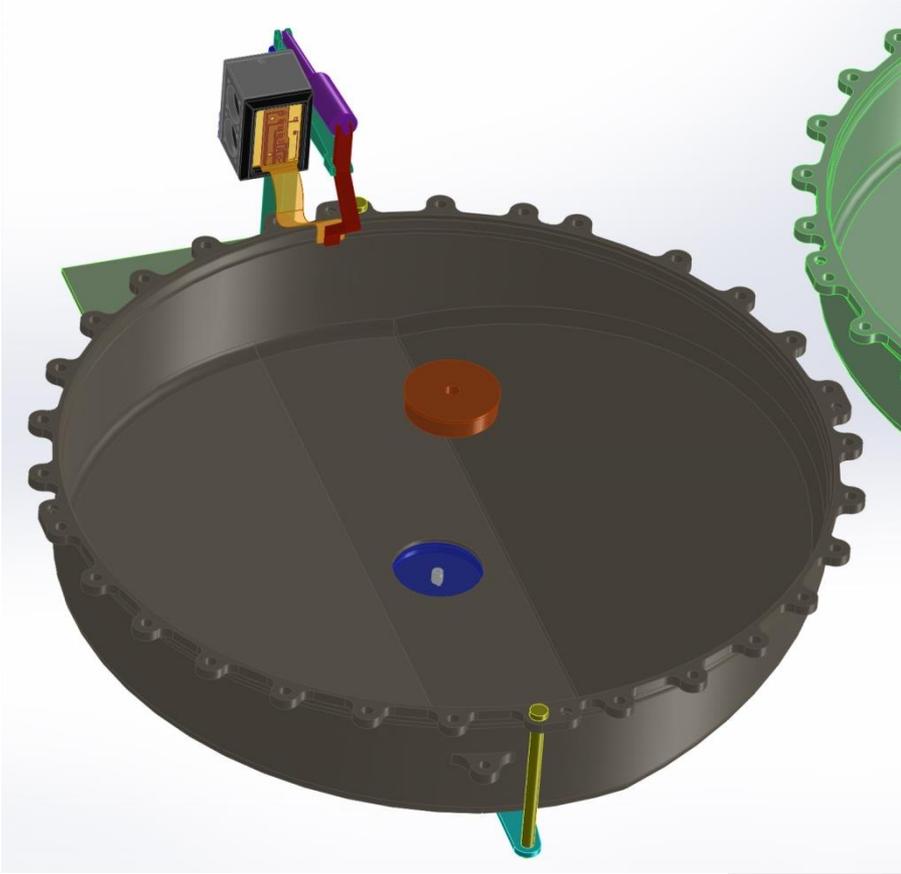
Blending of Corroded Sites on Flange



*Cold Spray Repair of
Inside Diameter of
Flange*

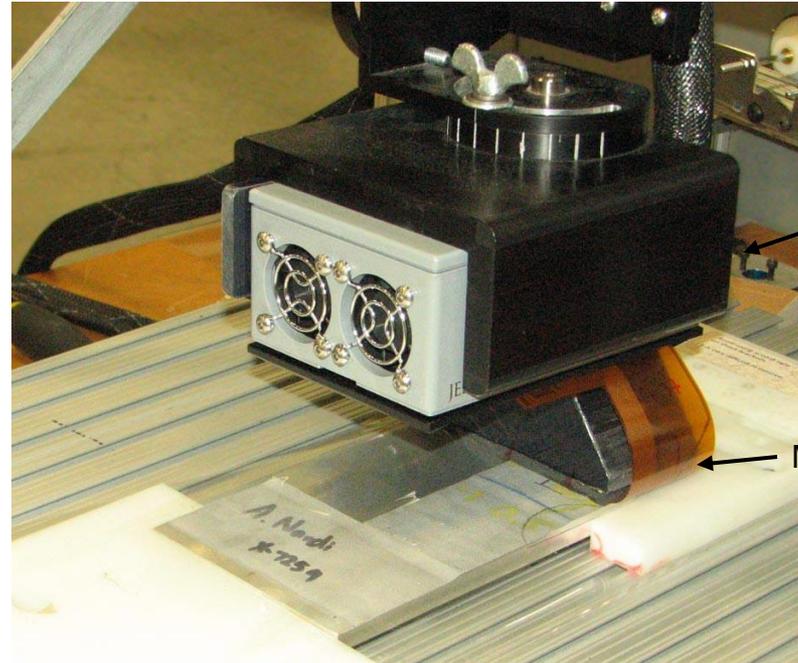
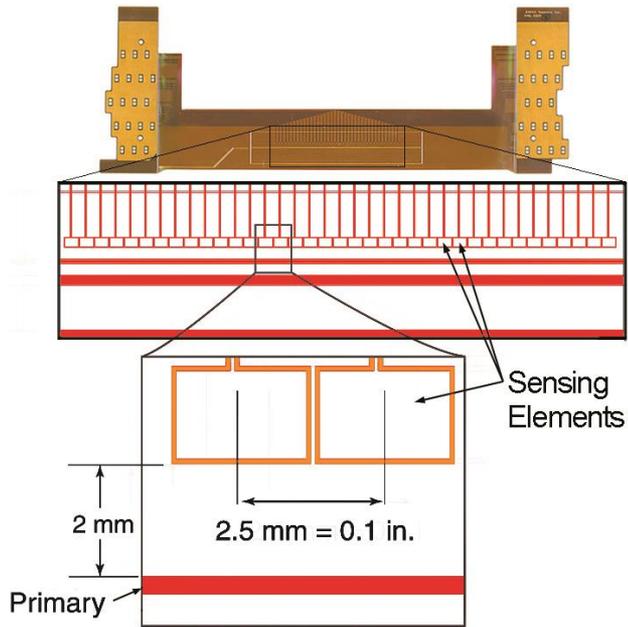
Source: www.asetdefense.org/documents/Workshops/SustainableSurfaceEngineering2009/Agenda/Wednesday/Gabriel%20-%20For%20Posting.pdf

Scanning Concept



MWM-Array FA24 Scans on Simulated Disbond Sample

MWM-Array FA24



MWM-Array Probe

MWM-Array FA24 Sensor

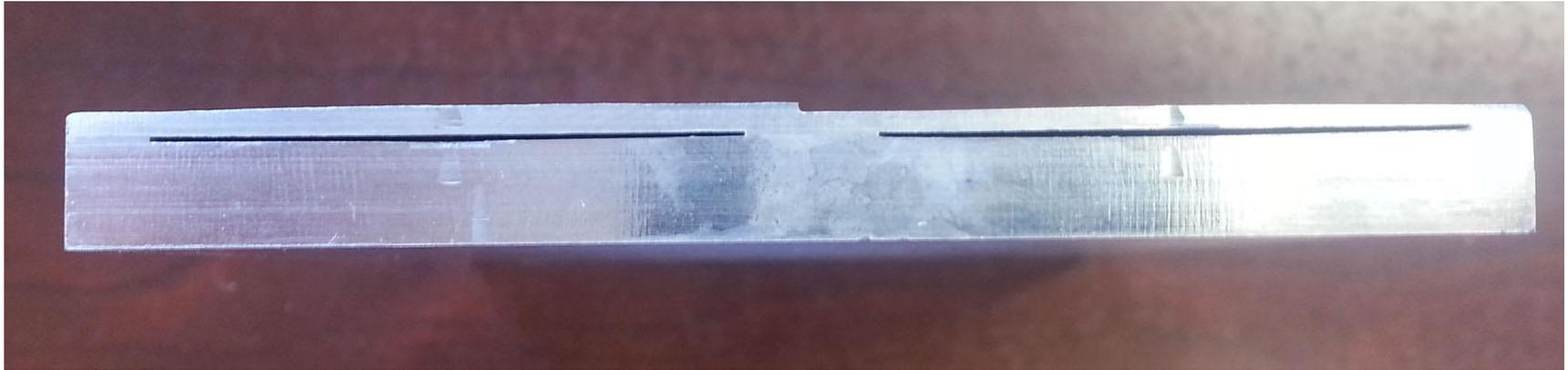


ARL Sample



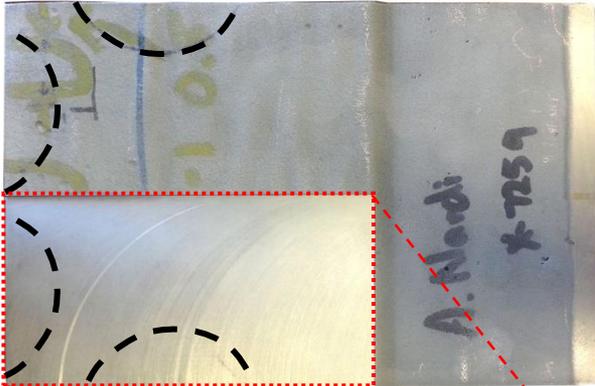
Nominal Dimensions

- Al Cold-Spray Thickness: 70 mils (1.8 mm)
- Delamination Gap: 10 mils (0.25 mm)
- Mg Substrate Thickness: 275 mils (7 mm)

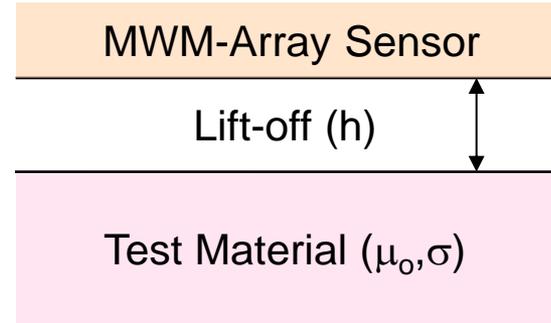


Preliminary "Disbond" Imaging Results

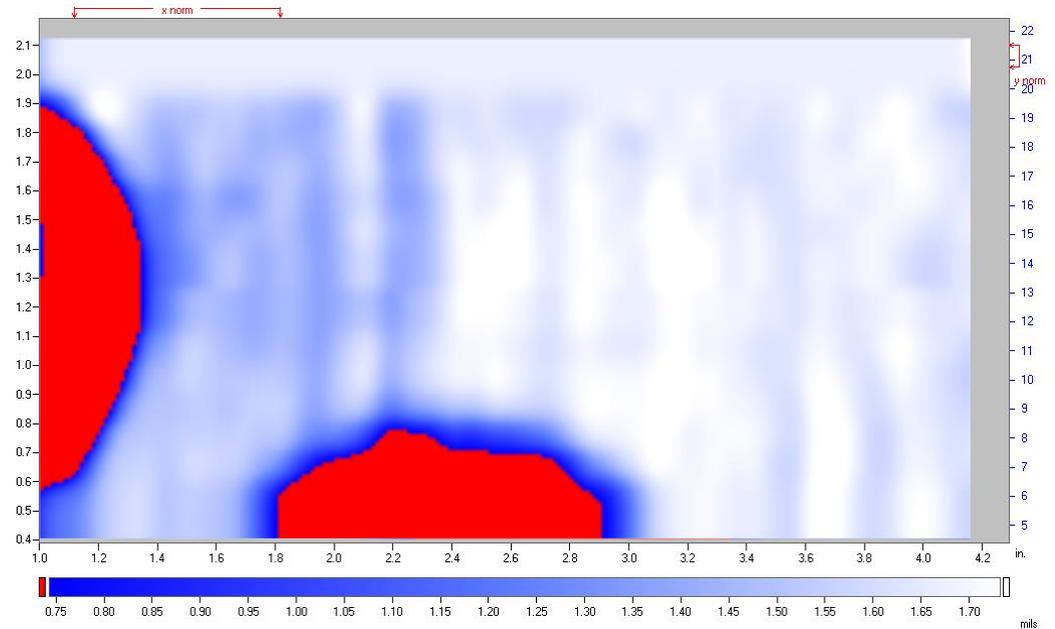
ARL Sample



Model



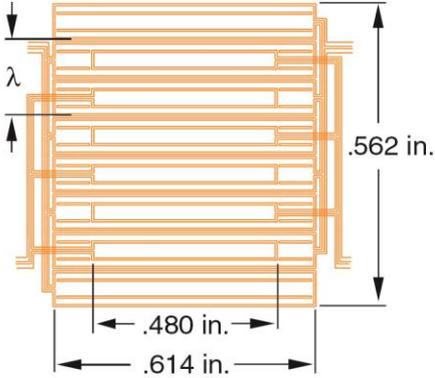
Scan Direction



MWM Coating Thickness Measurement & Q.A.



Single Sensing
Element MWM Sensor FS33



Right Angle
Adapter

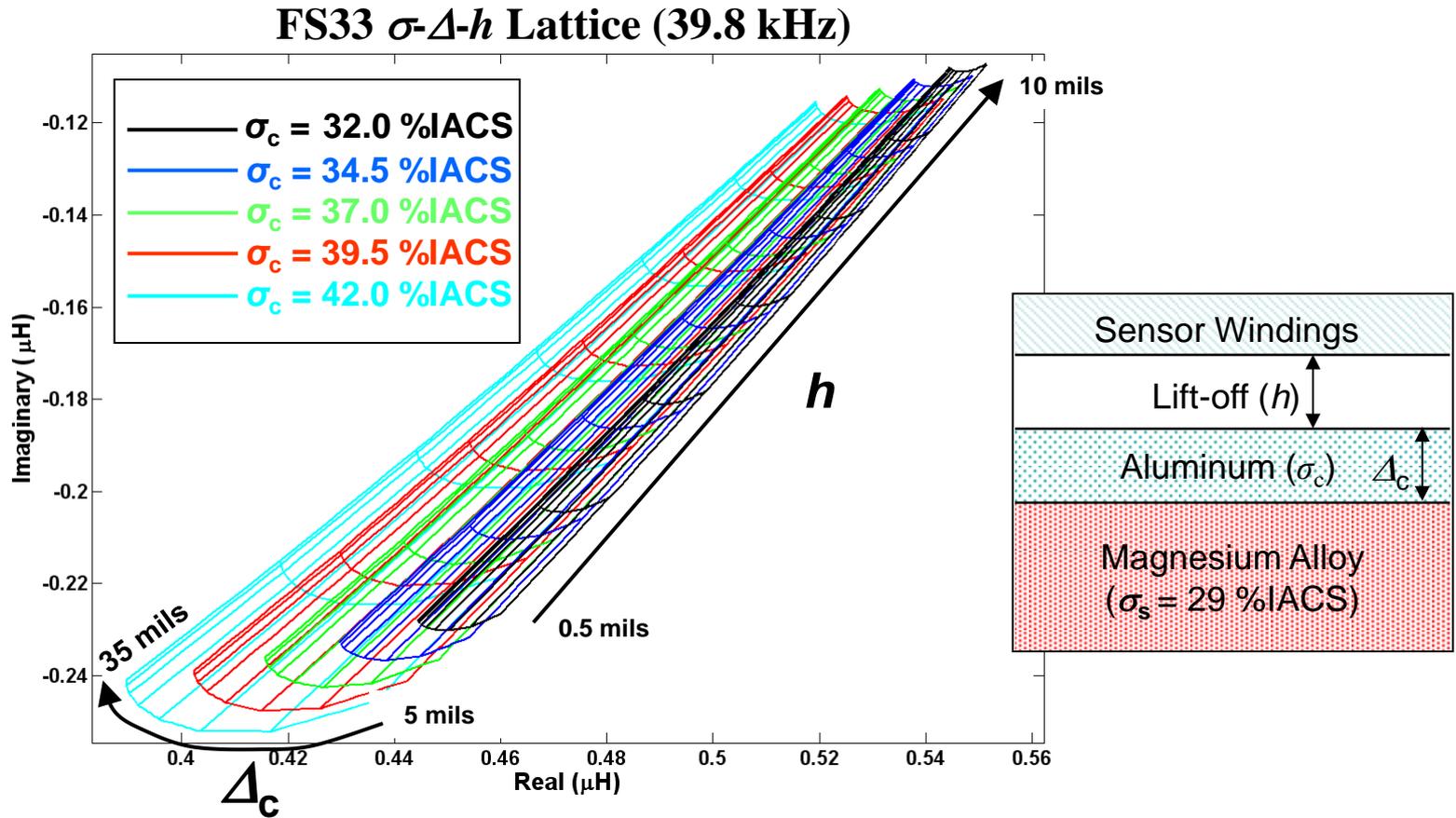


Calibration
Shunt Tip

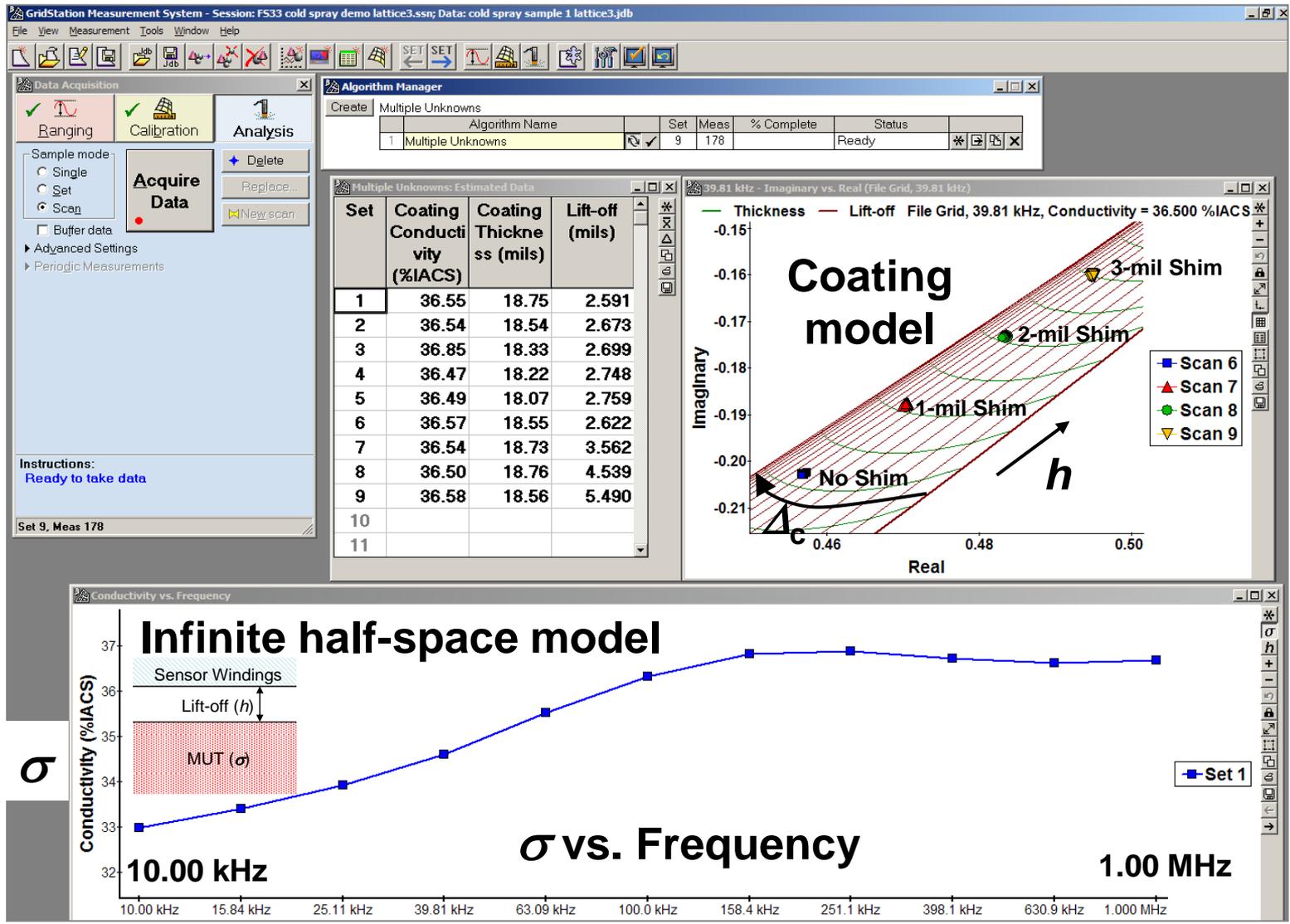


MWM
Sensor Tip

Measurement Lattice for Coating Characterization



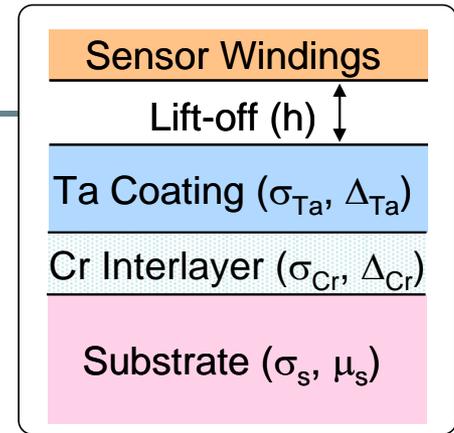
Coating Thickness & Conductivity Measurement Results



Benet Labs Problem Definition

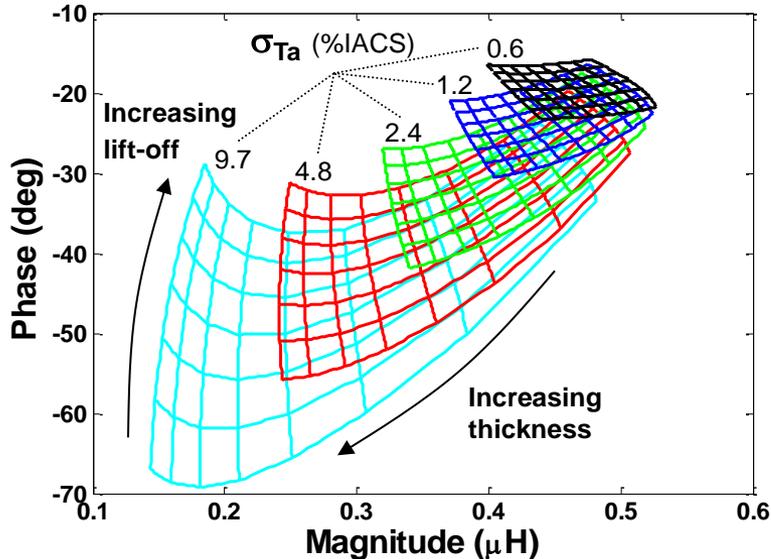
(Gun Barrel Coatings)

- Measure Four Unknowns
- Provide high resolution image of **each unknown**
- Automated & Real-Time



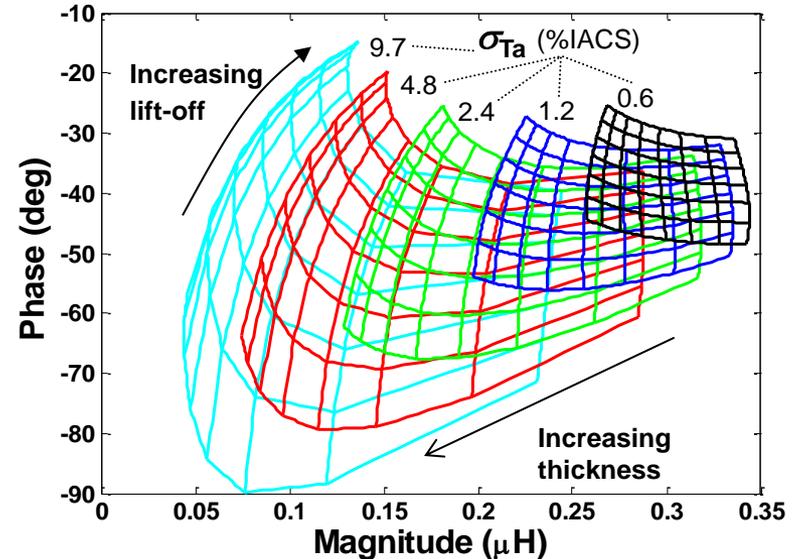
Low f σ_{Ta} - Δ_{Ta} - h Lattice

μ_s , σ_s , σ_{Cr} , δ_{Cr} constant



High f σ_{Ta} - Δ_{Ta} - h Lattice

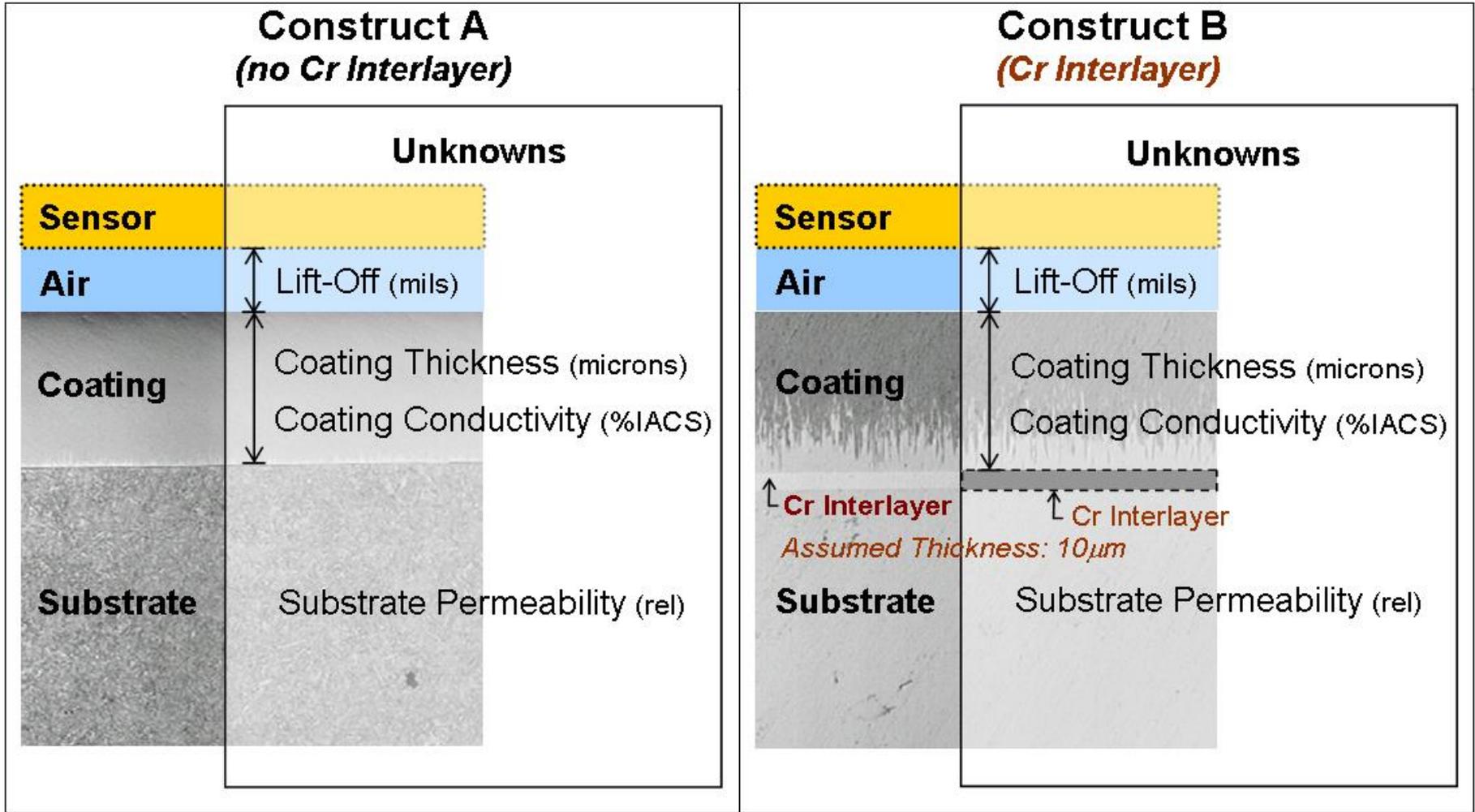
μ_s , σ_s , σ_{Cr} , δ_{Cr} constant



Zilberstein, V., Evans, L., Huguenin, C., Grundy, D., Shay, I., Goldfine, N., Mulligan, C., "Quality Assessment of Refractory Protective Coatings using Multi-Frequency Eddy Current MWM-Arrays," QNDE Conference, August 2005, AIP Conference Proceedings, Vol. 25B, pp 1067-1074, 2006.

Benet Labs Problem Definition

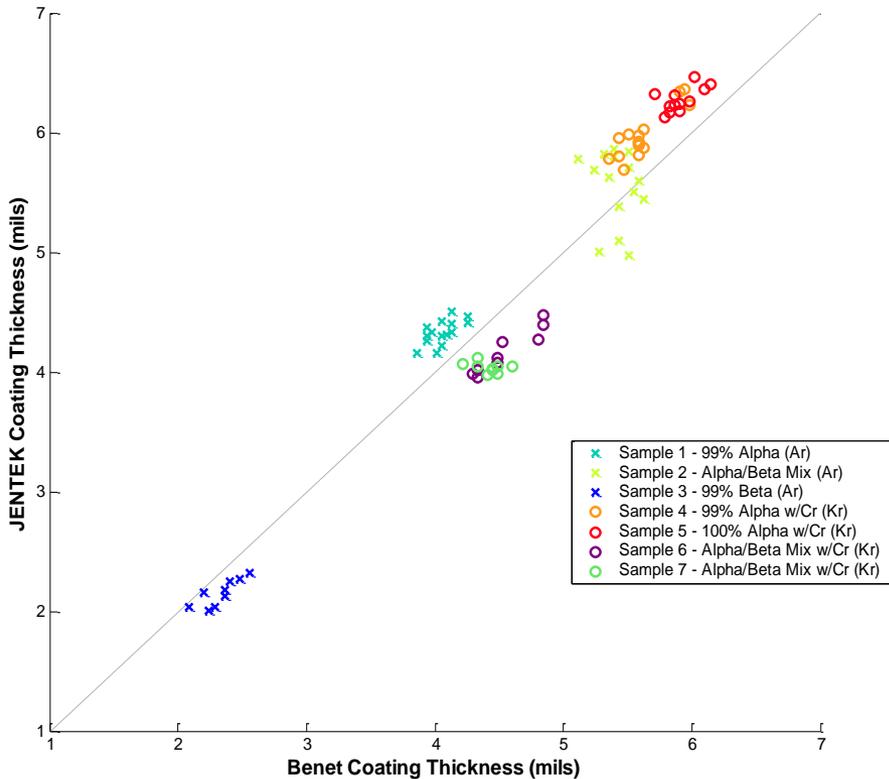
Schematics of 4-Unknown Constructs



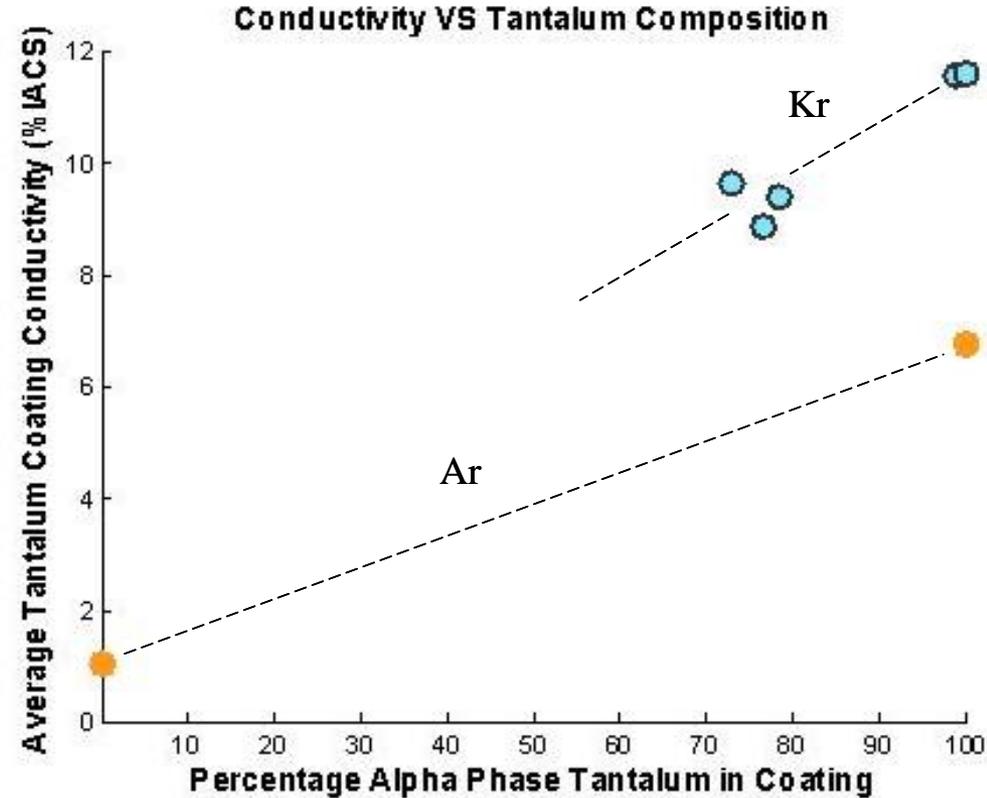
Zilberstein, V., Evans, L., Huguenin, C., Grundy, D., Shay, I., Goldfine, N., Mulligan, C., "Quality Assessment of Refractory Protective Coatings using Multi-Frequency Eddy Current MWM-Arrays," QNDE Conference, August 2005, AIP Conference Proceedings, Vol. 25B, pp 1067-1074, 2006.

Benet Labs Program Results

MWM-Array Measured Tantalum Coating Thickness Values



Conductivity vs. Phase Composition for Tantalum Coatings

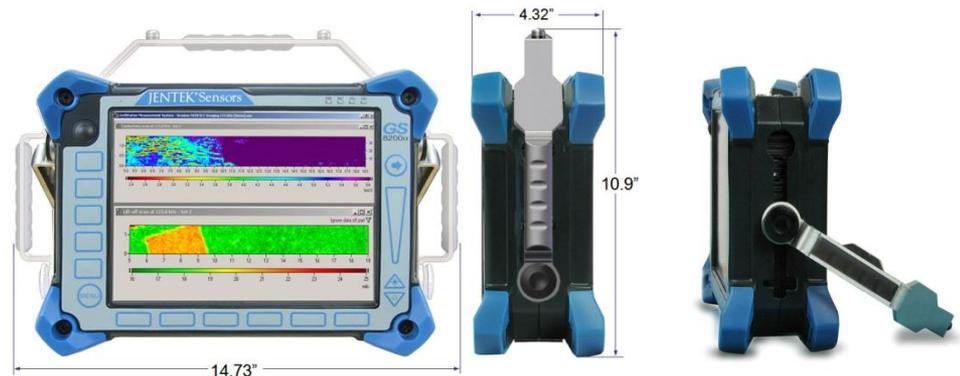
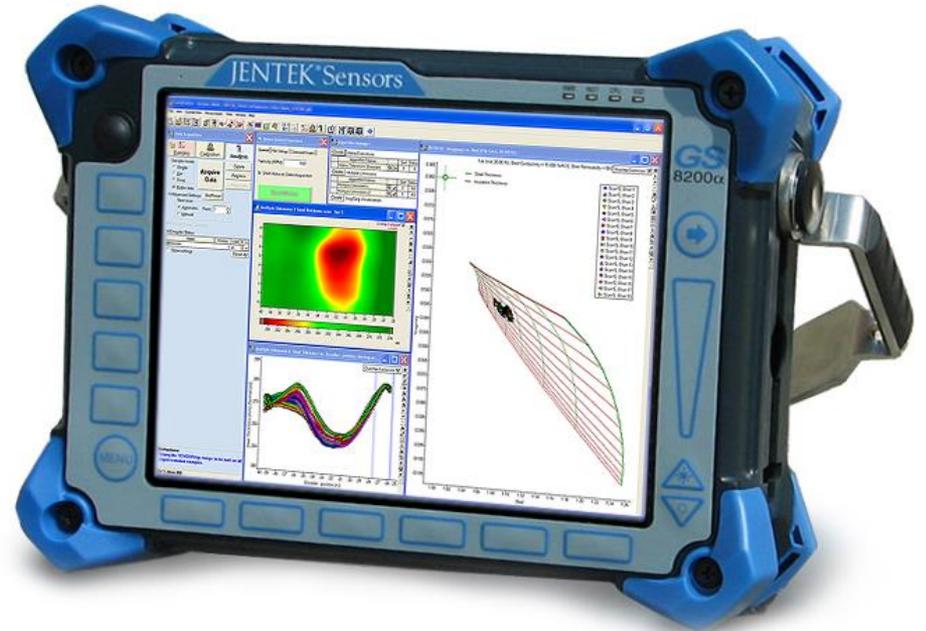


Zilberstein, V., Evans, L., Huguenin, C., Grundy, D., Shay, I., Goldfine, N., Mulligan, C., "Quality Assessment of Refractory Protective Coatings using Multi-Frequency Eddy Current MWM-Arrays," QNDE Conference, August 2005, AIP Conference Proceedings, Vol. 25B, pp 1067-1074, 2006.

GridStation 8200 α System

Available for purchase as commercial product in early 2014

- 19 to 118 channel standard configuration
- 100x faster
- 10x Improved signal-to-noise
- 5Hz - 20MHz operating frequency
- Windows[®] 8 operating system
- Intel Core i7, 3rd gen
- Multi-touch screen
- Weight: 8 lbs.
- Weight with probe electronics unit (PEU): 12 lbs



Questions?

Phone: 781-642-9666

www.jenteksensors.com

The views and opinions expressed in this presentation are those of the authors, and do not necessarily represent official policy or position of JENTEK Sensors, Inc., or any Department of the U.S. Government.